

STS6PF30L

P-CHANNEL 30V - 0.027Ω - 6A SO-8STripFET™ POWER MOSFET

TYPE	V _{DSS}	R _{DS(on)}	I _D
STS6PF30L	30 V	<0.030 Ω	6 A

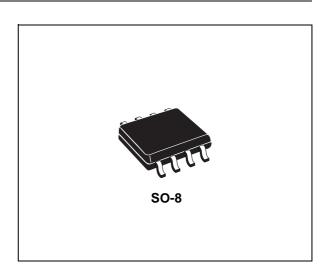
- TYPICAL $R_{DS}(on) = 0.027 \Omega$
- STANDARD OUTLINE FOR EASY AUTOMATED SURFACE MOUNT ASSEMBLY
- LOW THRESHOLD DRIVE

DESCRIPTION

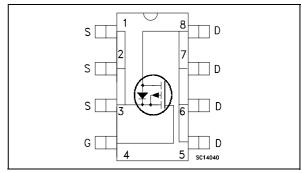
This Power MOSFET is the latest development of STMicroelectronis unique "Single Feature Size™" strip-based process. The resulting transistor shows extremely high packing density for low onresistance, rugged avalanche characteristics and less critical alignment steps therefore a remarkable manufacturing reproducibility.

APPLICATIONS

- MOBILE PHONE APPLICATIONS
- DC-DC CONVERTERS
- BATTERY MANAGEMENT IN NOMADIC **EQUIPMENT**



INTERNAL SCHEMATIC DIAGRAM



ABSOLUTE MAXIMUM RATINGS

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Australia - Brazil - China - Finland - France - Germany - Hong Kong - In Total Dissipation at T_C = 25°C Ptot

(•) Pulse width limited by safe operating area.

Note: For the P-CHANNEL MOSTEPTE a Street powerflay of witzerland - Ur voltages and current has to be reversed http://www.st.com http://www.st.com

May 2003 1/8

THERMAL DATA

Rthj-amb Thermal Resistance Junction-ambient Maximum Lead Temperature For Soldering Purpose storage temperature	Max Typ	50 150 -55 to 150	°C/W °C
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ELECTRICAL CHARACTERISTICS (T_{case} = 25 °C unless otherwise specified)

OFF

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
V _{(BR)DSS}	Drain-source Breakdown Voltage	$I_D = 250 \ \mu\text{A}, \ V_{GS} = 0$	30			V
I _{DSS}	Zero Gate Voltage Drain Current (V _{GS} = 0)	$V_{DS} = Max Rating$ $V_{DS} = Max Rating T_C = 125^{\circ}C$			1 10	μA μA
I _{GSS}	Gate-body Leakage Current (V _{DS} = 0)	V _{GS} = ± 16 V			±100	nA

ON (*)

Symb	ol Parameter	Test C	Test Conditions		Тур.	Max.	Unit
V _{GS(t}	Gate Threshold Voltage	$V_{DS} = V_{GS}$	$I_D = 250 \mu A$	1	1.6	2.5	V
R _{DS(o}	Static Drain-source On Resistance	V _{GS} = 10 V V _{GS} = 5 V	I _D = 3 A I _D = 3 A		0.027 0.034	0.030 0.042	Ω

DYNAMIC

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
g _{fs} (*)	Forward Transconductance	V_{DS} =10 V I_{D} =3 A		12		S
C _{iss} C _{oss} C _{rss}	Input Capacitance Output Capacitance Reverse Transfer Capacitance	$V_{DS} = 25V$, $f = 1 MHz$, $V_{GS} = 0$		1670 345 120		pF pF pF

ELECTRICAL CHARACTERISTICS (continued)

SWITCHING ON(*)

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
t _{d(on)} t _r	Turn-on Delay Time Rise Time	$\begin{aligned} V_{DD} &= 15 \text{ V} & I_D &= 3 \text{ A} \\ R_G &= 4.7 \Omega & V_{GS} &= 5 \text{ V} \\ \text{(Resistive Load, Figure 1)} \end{aligned}$		62 140		ns ns
Q _g Q _{gs} Q _{gd}	Total Gate Charge Gate-Source Charge Gate-Drain Charge	V _{DD} = 24V I _D = 6A V _{GS} =5V (see test circuit, Figure 2)		21 3.9 8.6	28	nC nC nC

SWITCHING OFF(*)

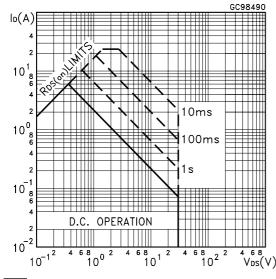
Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
t _{d(off)} t _f	Turn-off Delay Time Fall Time	$\begin{aligned} &V_{DD} = 24 \text{ V} & I_{D} = 3 \text{ A} \\ &R_{G} = 4.7\Omega, &V_{GS} = 5 \text{ V} \\ &(\text{Resistive Load, Figure 1}) \end{aligned}$		57 19		ns ns

SOURCE DRAIN DIODE(*)

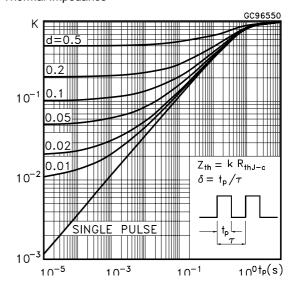
Symbol	Parameter	Test Conditions		Min.	Тур.	Max.	Unit
I _{SD}	Source-drain Current Source-drain Current (pulsed)					6 4	A A
V _{SD} (*)	Forward On Voltage	I _{SD} = 6 A	V _{GS} = 0			1.2	V
t _{rr} Q _{rr} I _{RRM}	Reverse Recovery Time Reverse Recovery Charge Reverse Recovery Current	I _{SD} = 6 A V _{DD} = 15 V (see test circu	di/dt = $100A/\mu s$ $T_j = 150^{\circ}C$ iit, Figure 3)		37 46.3 2.5		ns nC A

^(*)Pulse width \leq 300 µs, duty cycle 1.5 %. (•)Pulse width limited by T_{JMAX}

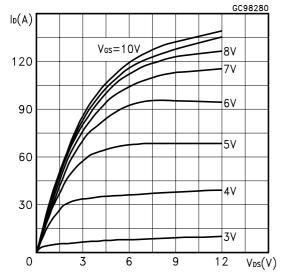
Safe Operating Area



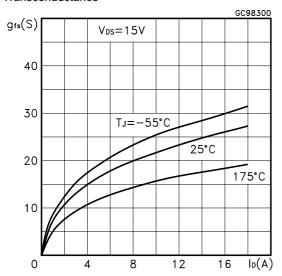
Thermal Impedance



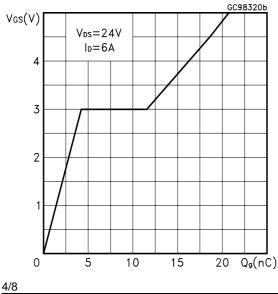
Output Characteristics



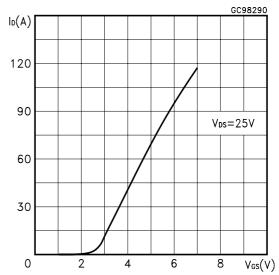
Transconductance



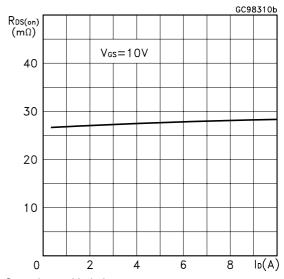
Gate Charge vs Gate-source Voltage



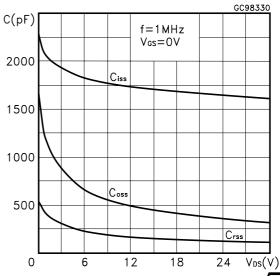
Transfer Characteristics



Static Drain-source On Resistance

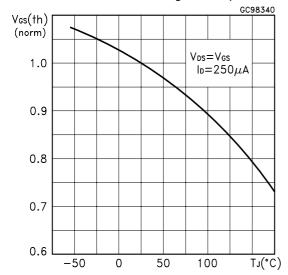


Capacitance Variations

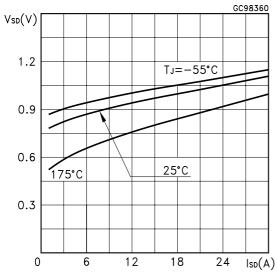


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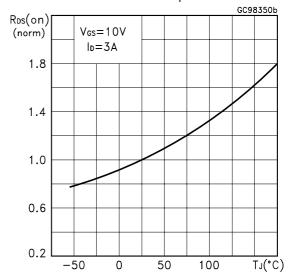
Normalized Gate Threshold Voltage vs Temperature



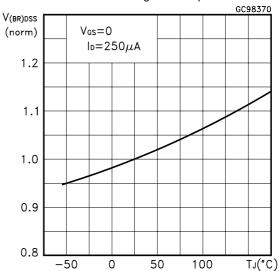
Source-drain Diode Forward Characteristics



Normalized on Resistance vs Temperature



Normalized Breakdown Voltage vs Temperature



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Fig. 1: Switching Times Test Circuits For Resistive Load

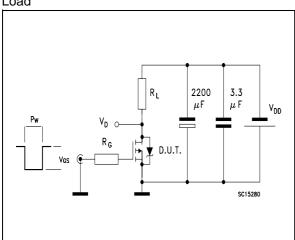


Fig. 2: Gate Charge test Circuit

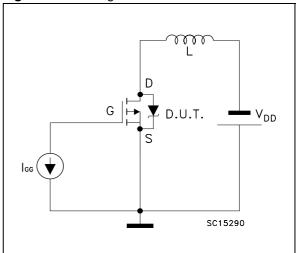
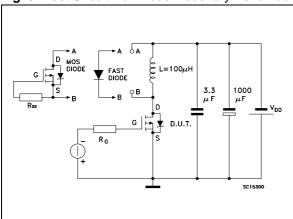
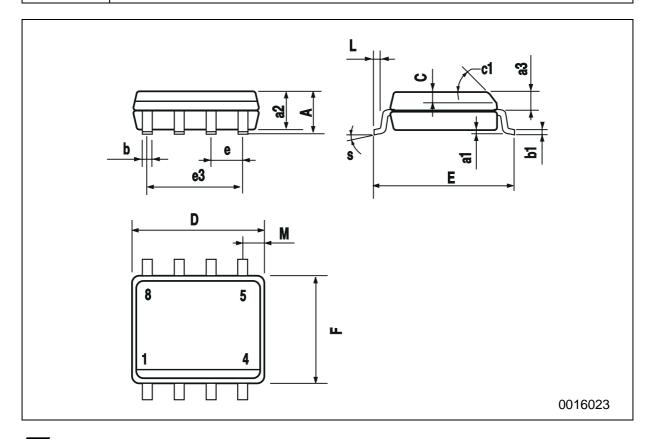


Fig. 3: Test Circuit For Diode Recovery Behaviour



SO-8 MECHANICAL DATA

DIM.		mm			inch	
Dilvi.	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.
Α			1.75			0.068
a1	0.1		0.25	0.003		0.009
a2			1.65			0.064
a3	0.65		0.85	0.025		0.033
b	0.35		0.48	0.013		0.018
b1	0.19		0.25	0.007		0.010
С	0.25		0.5	0.010		0.019
c1			45	(typ.)		
D	4.8		5.0	0.188		0.196
Е	5.8		6.2	0.228		0.244
е		1.27			0.050	
e3		3.81			0.150	
F	3.8		4.0	0.14		0.157
L	0.4		1.27	0.015		0.050
М			0.6			0.023
S			8 (1	max.)		



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